

AM4400N-T1-PF-VB Datasheet N-Channel 60-V (D-S) MOSFET

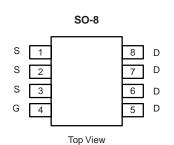
PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)			
60	0.025 at V _{GS} = 10 V	7.6	10.5 nC			
00	0.035 at V _{GS} = 4.5 V	6.5	10.5110			

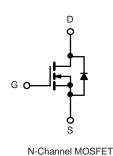
FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- Optimized for "Low Side" Synchronous Rectifier Operation
- 100 % R_g and UIS Tested



ROHS
COMPLIANT
HALOGEN
FREE





APPLICATIONS

CCFL Inverter

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	60	\/	
Gate-Source Voltage	V _{GS}	± 20	V	
	T _C = 25 °C		7.6 ^a	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	1 , 🗀	6.8	
Continuous Diain Current (1) = 150 °C)	T _A = 25 °C	l _D	6.1 ^{b, c}	
	T _A = 70 °C		4.8 ^{b, c}	
Pulsed Drain Current	I _{DM}	25	A	
Continuous Course Dunin Diada Courset	T _C = 25 °C	1	4.2	
Continuous Source-Drain Diode Current	T _A = 25 °C	l _s –	2.1 ^{b, c}	
Avalanche Current	. 0.4	I _{AS}	15	
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	11.2	mJ
	T _C = 25 °C		5	
Manianum Danum Dissipation	T _C = 70 °C		3.2	w
Maximum Power Dissipation	T _A = 25 °C	P _D	2.5 ^{b, c}	VV
	T _A = 70 °C		1.6 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	38	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	20	25		

Notes:

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				•			
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		55		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$\Delta V_{GS(th)}/T_J$ $I_D = 250 \mu\text{A}$		- 6.3		mv/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zoro Coto Voltago Proin Current	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V			1 μΔ		
Zero Gate Voltage Drain Current		V _{DS} = 60 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25			Α	
Davis Ossans Os Otata Basista sa	D	V _{GS} = 10 V, I _D = 4.6 A	0.025				
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 4.2 \text{ A}$		0.035		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 4.6 A		20		S	
Dynamic ^b							
Input Capacitance	C _{iss}			1100		pF	
Output Capacitance	C _{oss}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		90			
Reverse Transfer Capacitance	C _{rss}			55			
Total Cata Charge		$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 4.6 \text{ A}$		21	32		
Total Gate Charge	$Q_g = \frac{v_{DS} - v_{SS} - v_{SS}}{v_{SS}}$			10.5	16	nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = 30 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 4.6 \text{ A}$		3.5			
Gate-Drain Charge	Q _{gd}			4.2			
Gate Resistance	R_g	f = 1 MHz		3.3	5	Ω	
Turn-On Delay Time	t _{d(on)}			20	30		
Rise Time	t _r	$V_{DD} = 30 \text{ V}, R_{L} = 5.4 \Omega$		150	225		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 5.6 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		20	30		
Fall Time	t _f			60	90	20	
Turn-On Delay Time	t _{d(on)}			10	15	ns	
Rise Time	t _r	$V_{DD} = 30 \text{ V, R}_{L} = 5.4 \Omega$		15	25		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 5.6 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		25	40		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characterist	ics		•				
Continous Source-Drain Diode Current	I _S	T _C = 25 °C			4.2	۸	
Pulse Diode Forward Current ^a	I _{SM}				25	Α	
Body Diode Voltage	V _{SD}	I _S = 2 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	-		25	50	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	0		25	50	nC	
Reverse Recovery Fall Time	t _a	$I_F = 5.5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °\text{C}$		19		200	
Reverse Recovery Rise Time	t _b			6	İ	ns	

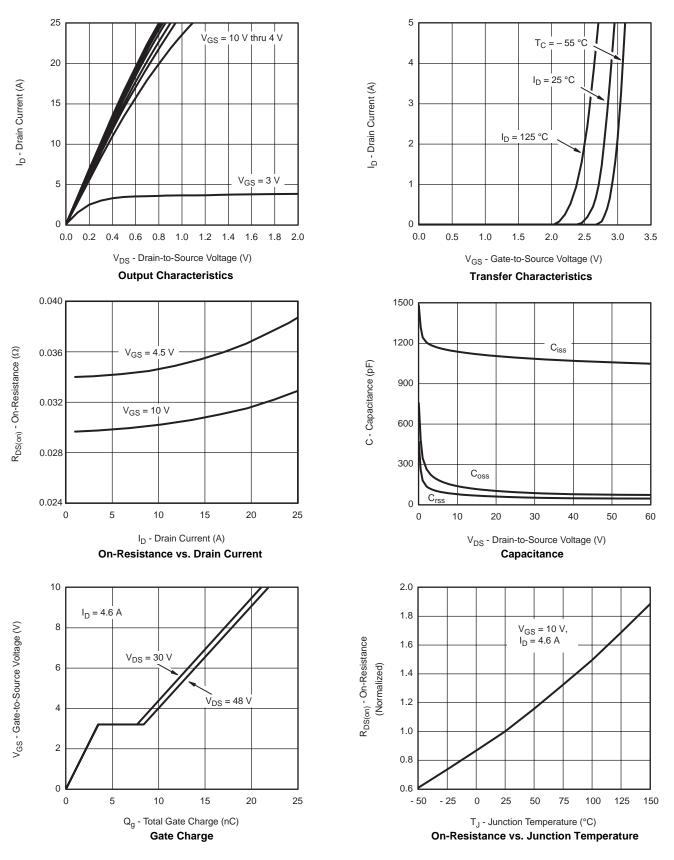
Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

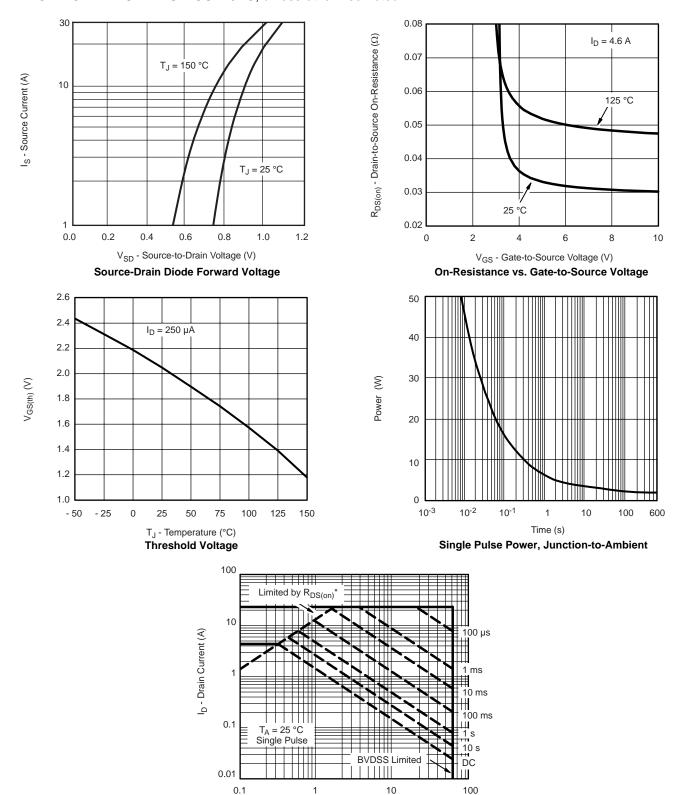
a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.





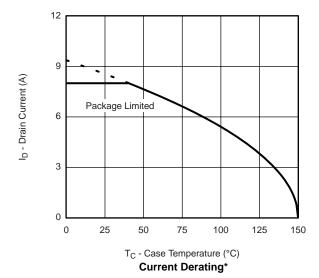


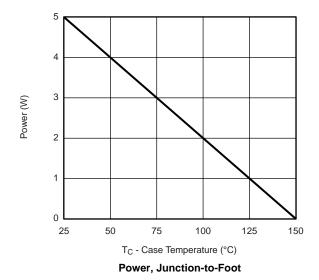


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$$\begin{split} & \text{V_{DS} - Drain-to-Source Voltage (V)$} \\ ^* \text{$V_{GS}$ > minimum V_{GS} at which $R_{DS(on)}$ is specified} \\ & \textbf{Safe Operating Area} \end{split}$$

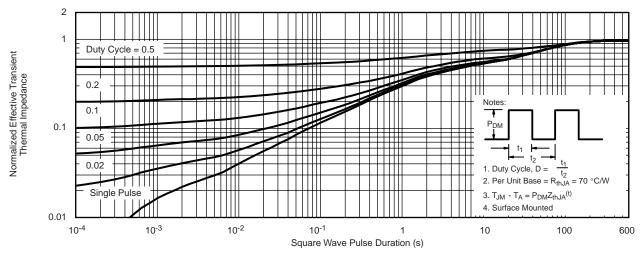




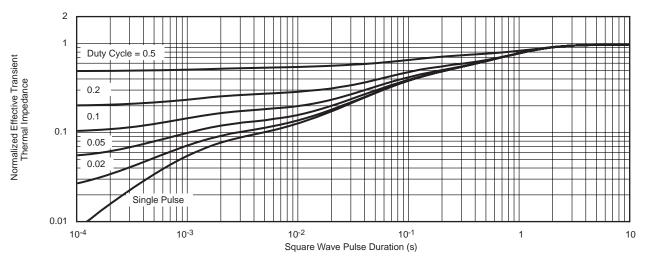


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







	MILLIN	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Pey I 11-Sep-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

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